



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. TRNDP013	Application No.: 10/683,554
	Applicant: Liang et al. Filing Date October 9, 2003	Group 2131

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
PwK	A	5,623,600	4/22/97	Ji et al.			9/26/95
	B						
	C						
	D						
	E						
	F						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
PwK	J	EP 1 335 559 A2	13.08.2003	European Patent Office			X	
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner /Paula Klimach/		REVIEWED By Paula Klimach at 11:01 am, Mar 28, 2007

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. TRNDP013	Application No.: 10/683,554
	Applicant: Liang	Group 2184
	Filing Date 10/09/03	

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
PwK	A	2003/145228	07/31/03	Suuronen et al.			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
PwK	J	03/014932	20.02.03	PCT				
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
PwK	O	Hameroff, "A holistic approach to enterprise security", Unisys World, 'Online! May 2003.
PwK	P	White et al., "Anatomy of a Commercial-Grade Immune System", IBM Research White Paper, June 1999.
	Q	
Examiner /Paula Klimach/		REVIEWED <i>Cite Considered</i> By Paula Klimach at 11:02 am, Mar 28, 2007

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.